PALM INTRANET

Inventor Name Search Result

Your Search was:

Last Name = WATKINS
First Name = CORY

Application#	Patent#	Status	Date Filed	Title	Inventor Name
09562273	6826298	150	04/29/2000	AUTOMATED WAFER DEFECT INSPECTION SYSTEM AND A PROCESS OF PERFORMING SUCH INSPECTION	WATKINS, CORY
09952537	6731383	150	09/12/2001	CONFOCAL 3D INSPECTION SYSTEM AND PROCESS	WATKINS, CORY
10073426	Not Issued	161	02/11/2002	Confocal 3D inspection system and process	WATKINS, CORY
10073613	6870609	150	02/11/2002	CONFOCAL 3D INSPECTION SYSTEM AND PROCESS	WATKINS, CORY
10073656	Not Issued	161	02/11/2002	Confocal 3D inspection system and process	WATKINS, CORY
10187295	6882415	150	07/16/2002	CONFOCAL 3D INSPECTION SYSTEM AND PROCESS	WATKINS, CORY
10196335	Not Issued	161	07/16/2002	Confocal 3D inspection system and process	WATKINS, CORY
10196349	Not Issued	164	07/16/2002	CONFOCAL 3D WAFER SURFACE INSPECTION SYSTEM	WATKINS, CORY
10196735	6970287	150	07/16/2002	CONFOCAL 3D INSPECTION SYSTEM AND PROCESS	WATKINS, CORY
10196741	6773935	150	07/16/2002	CONFOCAL 3D INSPECTION SYSTEM AND PROCESS	WATKINS, CORY
10623282	Not Issued	30	07/18/2003	Inspection tool with partial framing/windowing camera	WATKINS, CORY
10623283	Not Issued	30	07/18/2003	Inspection tool with partial framing camrea	WATKINS, CORY
10696871	Not Issued	161	10/30/2003	Confocal 3D inspection system and process	WATKINS, CORY
10890734	Not Issued	30	07/14/2004	Product setup sharing for multiple inspection systems	WATKINS, CORY

10890761	Not Issued	71	07/14/2004	Inspection and metrology module cluster tool	WATKINS, CORY
10890762	Not Issued	30	07/14/2004	Edge inspection	WATKINS, CORY
10890862	Not Issued	30	07/14/2004	Camera and illumination matching for inspection system	WATKINS, CORY
10890928	Not Issued	71	07/14/2004	Multi-tool manager	WATKINS, CORY
10915666	Not Issued	30	08/10/2004	Automated wafer defect inspection system and a process of performing such inspection	WATKINS, CORY
11146301	Not Issued	30	06/06/2005	System for generating camera triggers	WATKINS, CORY
11179019	Not Issued	30	07/11/2005	Camera module for an optical inspection system and related method of use	WATKINS, CORY
11179047	Not Issued	71	07/11/2005	Dynamic focusing method and apparatus	WATKINS, CORY
11179058	Not Issued	25	07/11/2005	Wafer holding mechanism	WATKINS, CORY
60232443	Not Issued	159	09/12/2000	Confocal 3D inspection system and process	WATKINS, CORY
60267862	Not Issued	159	02/09/2001	Confocal 3d inspection system and process	WATKINS, CORY
60268114	Not Issued	159	02/09/2001	Confocal 3d inspection system and process	WATKINS, CORY
60305729	Not Issued	159	07/16/2001	Confocal 3D inspection system and process	WATKINS, CORY
60305730	Not Issued	159	07/16/2001	Confocal 3D inspection system and process	WATKINS, CORY
60305823	Not Issued	159	07/16/2001	Confocal 3D inspection system and process	WATKINS, CORY
60375319	Not Issued	159	04/25/2002	Line scan or area scan camera with InfiniBand interface	WATKINS, CORY
60375321	Not Issued	159	04/25/2002	Standalone frame grabber with InfiniBand interface	WATKINS, CORY
60375365	Not Issued	159	04/25/2002	InfiniBand as a data backbone for inspection tool	WATKINS, CORY
60375366	Not Issued	159	04/25/2002	Aquiring image data from cameras onto InfiniBand network fabric	WATKINS, CORY
60375487	Not Issued	159	04/25/2002	InfiniBand image processing cluster	WATKINS, CORY

60375488	Not Issued	159	04/25/2002	Enhanced framegrabber with InfiniBand interface	WATKINS, CORY
60375517	Not Issued	159	04/25/2002	Use of InfiniBand linked image processing data center as a method for reducing COO by sharing image processing power across multiple tools	WATKINS, CORY
60375528	Not Issued	159	04/25/2002	CMOS sensor with built in InfiniBand interface	WATKINS, CORY
60397327	Not Issued	159	07/18/2002	Inspection tool with partial framing camera	WATKINS, CORY
60397328	Not Issued	159	07/18/2002	Inspection tool with partial framing/windowing camera	WATKINS, CORY
60414983	Not Issued	159	09/30/2002	Imaging system using theta-theta coordinate stage and continuous image rotation to compensate for stage rotation	WATKINS, CORY
60486949	Not Issued	159	07/14/2003	Camera and illumination matching for inspection system	WATKINS, CORY
60486953	Not Issued	18	07/14/2003	Edge inspection	WATKINS, CORY
60486955	Not Issued	159	07/14/2003	Inspection and metrology module cluster tool	WATKINS, CORY
60487152	Not Issued	159	07/14/2003	Product setup sharing for multiple inspection systems	WATKINS, CORY
60587116	Not Issued	159	07/12/2004	Dual chip camera	WATKINS, CORY
60587216	Not Issued	159	07/12/2004	Wafer backside inspection	WATKINS, CORY
60587302	Not Issued	159	07/12/2004	Pentaprism and flexure focusing mechanism	WATKINS, CORY
60587571	Not Issued	159	07/12/2004	Wafer clamping	WATKINS, CORY
60615626	Not Issued	159	10/04/2004	Advanced laser triangulation ("B")	WATKINS, CORY
60615770	Not Issued	159	10/04/2004	Rotary stage laser triangulation sensor scanning	WATKINS, CORY

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Inventor Name Search Result

Your Search was:

Last Name = WATKINS
First Name = CORY

Application#	Patent#	Status	Date Filed	Title	Inventor Name
60615836	Not Issued	159	10/04/2004	Advanced laser triangulation ("A")	WATKINS, CORY
60758522	Not Issued	20	01/12/2006	Color imaging using monochrome imagers	WATKINS, CORY
60788642	Not Issued	20	04/03/2006	Wafer bevel inspection mechanism	WATKINS, CORY
10423470	Not Issued	41	04/25/2003	Sensor with switched fabric interface	WATKINS, CORY M.
10423475	Not Issued	95	04/25/2003	Data transfer device with data frame grabber with switched fabric interface wherein data is distributed across network over virtual lane	WATKINS, CORY M.
10424143	Not Issued	25	04/25/2003	Switched fabric based inspection system	WATKINS, CORY M.
10675807	Not Issued	30	09/30/2003	Imaging system using theta-theta coordinate stage and continuous image rotation to compensate for stage rotation	WATKINS, CORY M.
60199226	Not Issued	159	04/24/2000	Non-contact wheel measuring system	WATKINS, CORY M.
60577544	Not Issued	159	06/07/2004	System for generating camera triggers	WATKINS, CORY M.

Inventor Search Completed: No Records to Display.

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EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	312	((inspect$3) or ((defect or flaw) with detect$3)) and (camera same row same pixel) and ((FOV) or (field with view))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/16 13:51
S2	2306	382/144,145,146,147,148,149,150, 151.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:31
S3	22	S1 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/08 11:09
S4	2	("20040096095").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/08 11:09
S5	2	("6773935").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:22
S6	2	("6970287").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:22
S7	2	("20030030794").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:25
S8	2	("6882415").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:26

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S9	2	("6870609").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:29
S10	2	("6731383").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:35
S11	2	("6826298").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/09 20:35
S12	2491	382/144,145,146,147,148,149,150, 151.ccls. 348/126,133,134.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 13:39
S13	1077	((inspect$3)) and (camera same (row or axis or line) same pixel) and ((FOV) or (field with view))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:55
S14	73	S12 and S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:52
S15	8545	(die or patter or circuit or device or part or chip or IC) same (greater or bigger or larger) same ((FOV) or (field with view))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:35
S16	45	S12 and S15	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:35

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S17	907	((inspect$3)) and (camera same (row or line) same pixel) and ((FOV) or (field with view))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 16:12
S18	59	S12 and S17	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 10:56
S19	2	("6522777").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/10 15:55
S20	2	("6522777").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/10 15:55
S21	2	("5646733").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/10 15:55
S22	777	((inspect$3)) and (camera same (row or line or horizontal) same (size or dimension or height or width) same (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 17:17
S23	394	((inspect$3)) and (camera same (read$1out or output$3 or generat$3 or produc$3) same (row or line or horizontal) same (size or dimension or height or width) same (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 17:18
S24	26	S12 and S23	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 16:16

S25	1703	(camera same (read$1out or output$3 or generat$3 or produc$3) same (row or line) same (size or dimension or height or width) same (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 17:36
S26	126	(camera with (read$1out or output$3 or generat$3 or produc$3) with (row or line)) same ((size or dimension or height or width) with (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 18:08
S27	18	"382"/$.ccls. and S26	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 17:38
S28	2	(camera with (read$1out or output$3 or generat$3 or produc$3) with ((row or line) and column)) same ((size or dimension or height or width) with (semiconductor or wafer or die or pattern))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/10 18:11
S29	2491	382/144,145,146,147,148,149,150, 151.ccls. 348/126,133,134.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:52
S30	28465	(camera or CCD) same (select$5 or choos$3 or pick$3) same (line or row or column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:54
S31	180	S29 and S30	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:54
S32	9163	(camera or CCD) with (select$5 or choos$3 or pick$3) with (line or row or column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:54

S33	65	S29 and S32	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/11 17:55
S34	3	("6661912").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 13:58
S35	2	("5541654").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 14:14
S36	2	("6867811").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 15:09
S37	2	("5097492").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 15:26
S38	429	camera and ((rows and columns) same (ROI or AOI or (region near5 interest) or (area near5 interest)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 15:27
S39	2491	382/144,145,146,147,148,149,150, 151.ccls. 348/126,133,134.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 15:27
S40	10	S38 and S39	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 17:37

S41	9102	(inspect$3) and (camera same (partial or part or fraction$3) same (frame or image))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 17:40
S42	275	S39 and S41	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 17:39
S43	1075	(inspect$3) and (camera same (partial or part or fraction$3) same (frame) same image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:11
S44	49	S39 and S43	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 17:40
S45	86	(inspect$3) and (camera same (partial) same (frame) same image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:42
S46	2	S39 and S45	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:11
S47	2	("4668982").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/14 18:44
S48	8	camera same (read$1out or generat$3 or output$3) same (size or dimension) same (semiconductor with die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:49

S49	1	camera same (rows and columns) same (size or dimension) same (semiconductor with die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/14 18:50
S50	6	camera and ((rows and columns) same (size or dimension) same (semiconductor with die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 11:16
S51	6	camera and ((rows and columns) same (size or dimension) same (semiconductor with die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 11:27
S52	31	(inspect$3 with semiconductor with substrate) and ((locat$3 or specif$5 or target$3 or AOI or ROI) with semiconductor with die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 11:33
S53	32	(inspect$3 with semiconductor with substrate) and ((identif$7 or look$3 or find$3) with semiconductor with die)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 11:58
S54	2	("6936835").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 11:58
S55	4	("4328553").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:40
S56	2	("4464705").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:40

S57	2	("4644172").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:44
S58	2	("4823394").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:45
S59	2	("5019963").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:46
S60	2	("5091963").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:46
S61	2	("5497381").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:47
S62	2	("5640200").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:48
S63	2	("5641960").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:49
S64	2	("5787190").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:49

S65	2	("5822055").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:51
S66	2	("5850466").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:52
S67	2	("5856844").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:53
S68	2	("5861910").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:54
S69	2	("5917588").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:56
S70	2	("5949901").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 13:56
S71	2	("6324298").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 15:54
S72	2	("5091963").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:14

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S73	2	("20030133604").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:15
S74	2	("6382323").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:16
S75	2	("6693664").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:24
S76	901	(inspect$4) and ((semiconductor with die) same (step$4 or repeat$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 17:26
S77	0	(inspect$4) and ((semiconductor with die) same (step$4 or repeat$3)) and ((fied near4 view) same ((smaller or less) and (greater or bigger or larger)) same (pattern or die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 17:29
S78	0	(inspect$4) and ((semiconductor with die) same (step$4 or repeat$3)) and ((fied near4 view) same (pattern or die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 17:30
S79	28	(inspect$4) and ((semiconductor with die) same (step$4 or repeat$3)) and ((field near4 view) same (pattern or die))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/15 17:56
S80	2	("5541654").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/15 17:58

EAST Search History

S81	2	("5694495").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/16 12:40
S82	2	("6693664").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/16 12:40
S83	0	(semiconducto with (die or pattern)) same (smaller or less) same ((field near3 view) or FOV)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/16 13:52
S84	20	(semiconductor with (die or pattern)) same (smaller or less) same ((field near3 view) or FOV)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/16 14:17
S85	2	("6457232").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/16 14:18